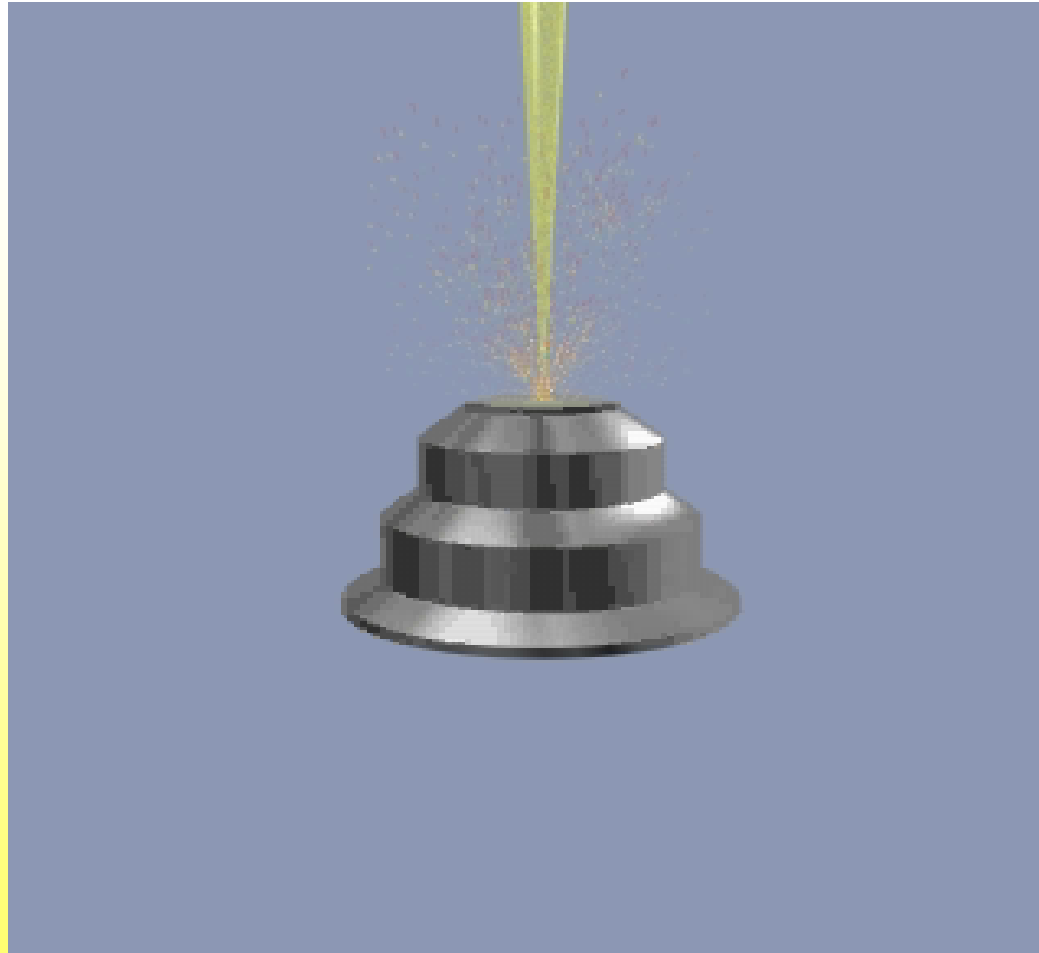


# Energy Dispersive Spectrometer ( X-rays)

能量分散光譜儀



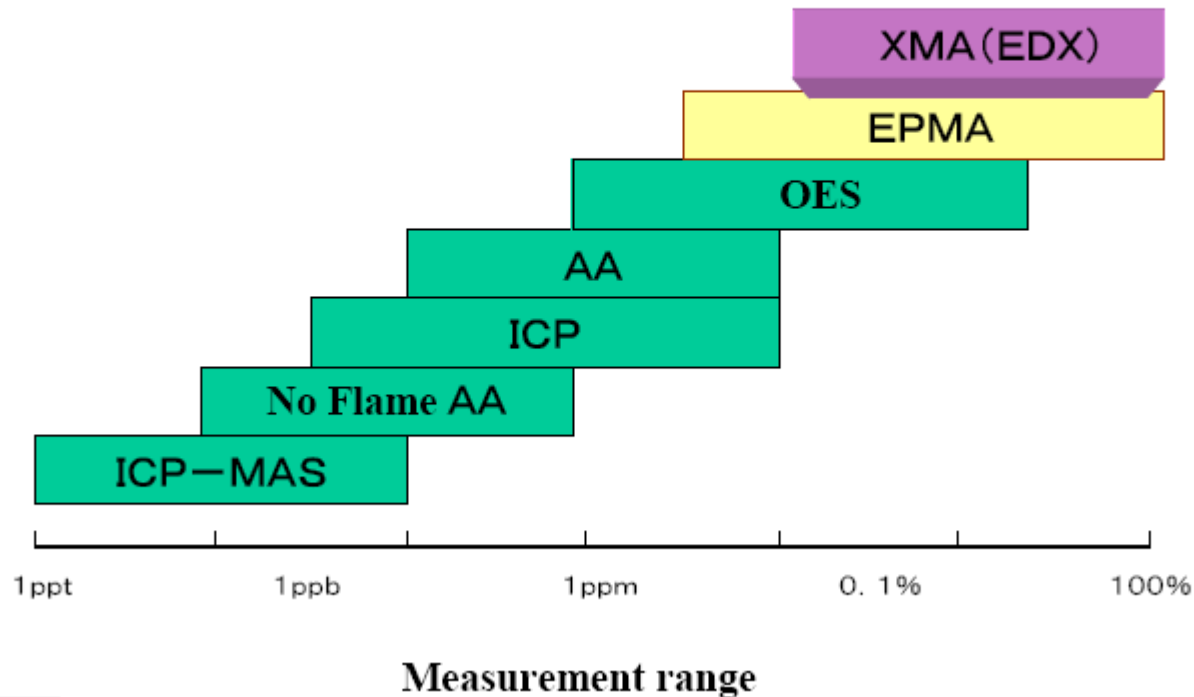
# Theory of Energy Dispersive

## 表面分析技術一般性之比較

分析技術	典型應用	偵測元素	偵測極限	取樣深度	平面解析	影像/成像
AES	Surface Analysis & Depth Profile	Li - U Chemical binding	0.1 ~ 1 at%	5 ~ 50Å	< 10nm	Y SEM/SAM
XPS	Surface Analysis & Depth Profile	Li - U Chemical binding	0.1 ~ 1 at%	5 ~ 75 Å	< 10µm	Y XPS mapping
SEM /EDS	Image & Elemental Microanalysis	B - U (EDS)	0.1 ~ 1 at%	1 ~ 5 µm (EDS)	< 1nm	Y Y
FIB	Cross / thin section, IC Design, Modification	-	-	200 Å	< 5nm	Y
XRD	Phase Identification		< 5%	> 600 Å	5mm	
TXRF	Metal Contamination on Si wafer	S - U	10 E9 ~ E11 at/cm <sup>2</sup>	5nm	10mm	Y
RBS	Quantitative Thin Film Composition & Thickness	LI ~ U	10 <sup>-1</sup> - 0.01 - 0.001 at% (Z: 20;70)	20 ~500Å	2mm	Y
SIMS	Dopant & Impurity Depth Profile, Surface, Micro-analysis	H - U	10E12 ~ E16 at/cm <sup>3</sup> (ppm ~ ppb)	50 ~ 300 Å	< 500Å	Y
SPM	Surface Imagine			0.1Å	< 10Å	Y

# Theory of Energy Dispersive Spectrometer

## *Classification of elemental analyzer*



# Theory of Energy Dispersive

## *What can you do with EDX analysis*

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### ◆ *Qualitative analysis*

• Range :  ${}_5\text{Be} \sim {}_{92}\text{U}$

### ◆ *Quantitative analysis*

• Quantitative analysis by XPP

• Na or more : 0.2~0.3wt%    C : about 1wt%

### ◆ *Mapping (DBC)*

• Multi-element simultaneous mapping

• Line analysis

• Phase analysis

### ◆ *Particle analysis by elements*

# Theory of Energy Dispersive Spectrometer

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*Pre-treatment sample*

# Theory of Energy Dispersive

## Fixation of a sample (powder)

Sample holder Carbon product (For observation ; Aluminum product)

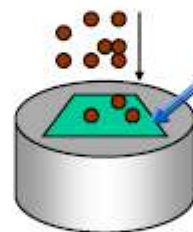
The charge of sample fixed material Carbon tape

For conductive processing Carbon paste Silver paste

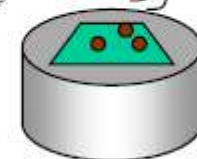


### ① The spatter method

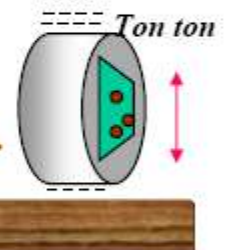
It observes and analyzes in the state.



Carbon tape



Excessive powder is blown away by blower



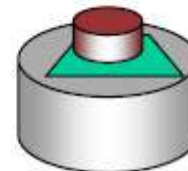
Excessive powder fails to be struck.

### ② The pressing method

It is suitable for the quantitative analysis.



Press machine



# Theory of Energy Dispersive

## *Fastening sample (massiveness sample)*

Sample holder

carbon



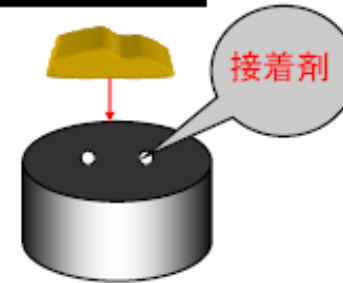
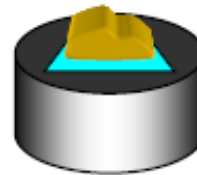
stuck material

carbon tape



### ① Stuck as it is

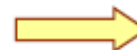
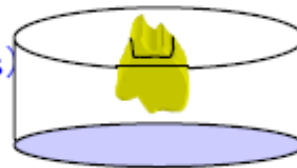
(そのまま観察、分析)



元素マッピングする場合は接着剤で  
確実に固定する

### ② buried in resin

(suitable for quantitative analysis)



試料を樹脂に埋め込む

鏡面研磨する(仕上げはダイヤモンドペースト等)

超音波洗浄で  
試料表面に残  
っている研磨粉  
を取り除く

# Theory of Energy Dispersive Spectrometer

## *Conductive processing of a sample*

---

### 1. A sample with conductivity

Especially this sample does not need a pretreatment.

However, it is required between a sample and a sample holder to give conductivity at a carbon tape or carbon paste..

### 2. A sample without conductivity

Carbon coating is performed to this in principle.

Gold and platinum coating are performed to this by the case.



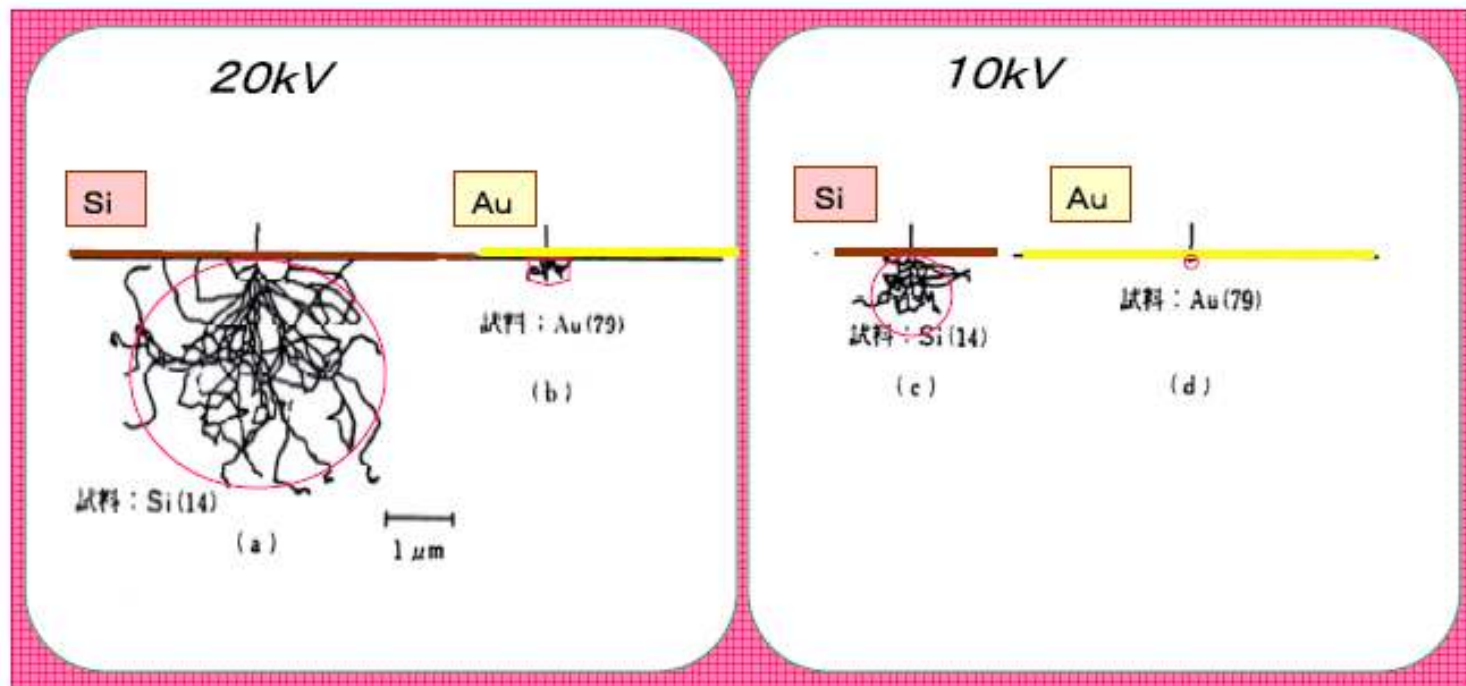
# Theory of Energy Dispersive

## *Influence which the composition element of materials and the accelerating voltage has on the analysis depth*

2196—6812—6/40

Although EDX analysis is called surface analysis, the X ray information in several micrometers depth is acquired on the average.

Deeper X ray information is acquired so that accelerating voltage is high, and, so that the average atomic number of a sample becomes low.,



# Theory of Energy Dispersive

## Coating

2196—6812—19/40

	Au/Pt	C
Image quality	○ Good	△ No Good
分析	△ X rays with small energy are absorbed in the coating layer	○ As for X rays of all energy, absorption in the coating layer is little
	× There are overlap peak	

# Theory of Energy Dispersive Spectrometer

Spectrometer

2196—6812—18/40

## Carbon, Gold, platinum Coating

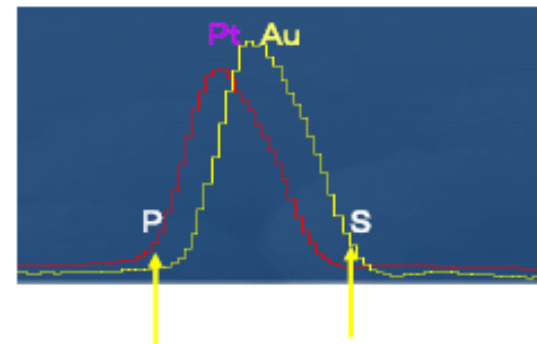
*In general, when you observe SEM image, you coat sample with Au, Pt.*

But you analyze element.

- ① Characteristic X-ray generated from light elements absorbed by coating layer.
- ② P(phosphorus) and Sulfur peak overlap Gold, Platinum peak.



**Carbon Coating**



# Theory of Energy Dispersive Spectrometer

2196-6812-20/4

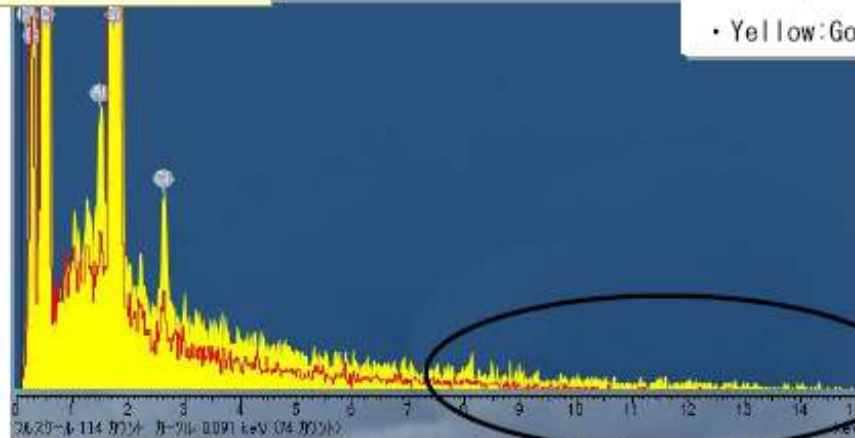
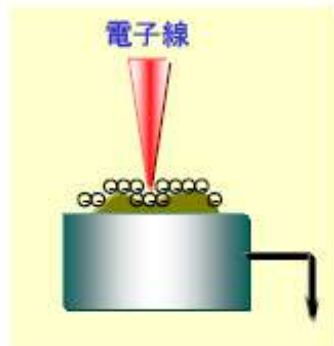
## Charge UP

Analysis : Not charge UP !!!

試料：紙

加速電圧：15kV

- Read : Charge UP
- Yellow : Good



SEM像：赤スペクトル  
(チャージアップあり)

SEM像：黄スペクトル  
(チャージアップなし)

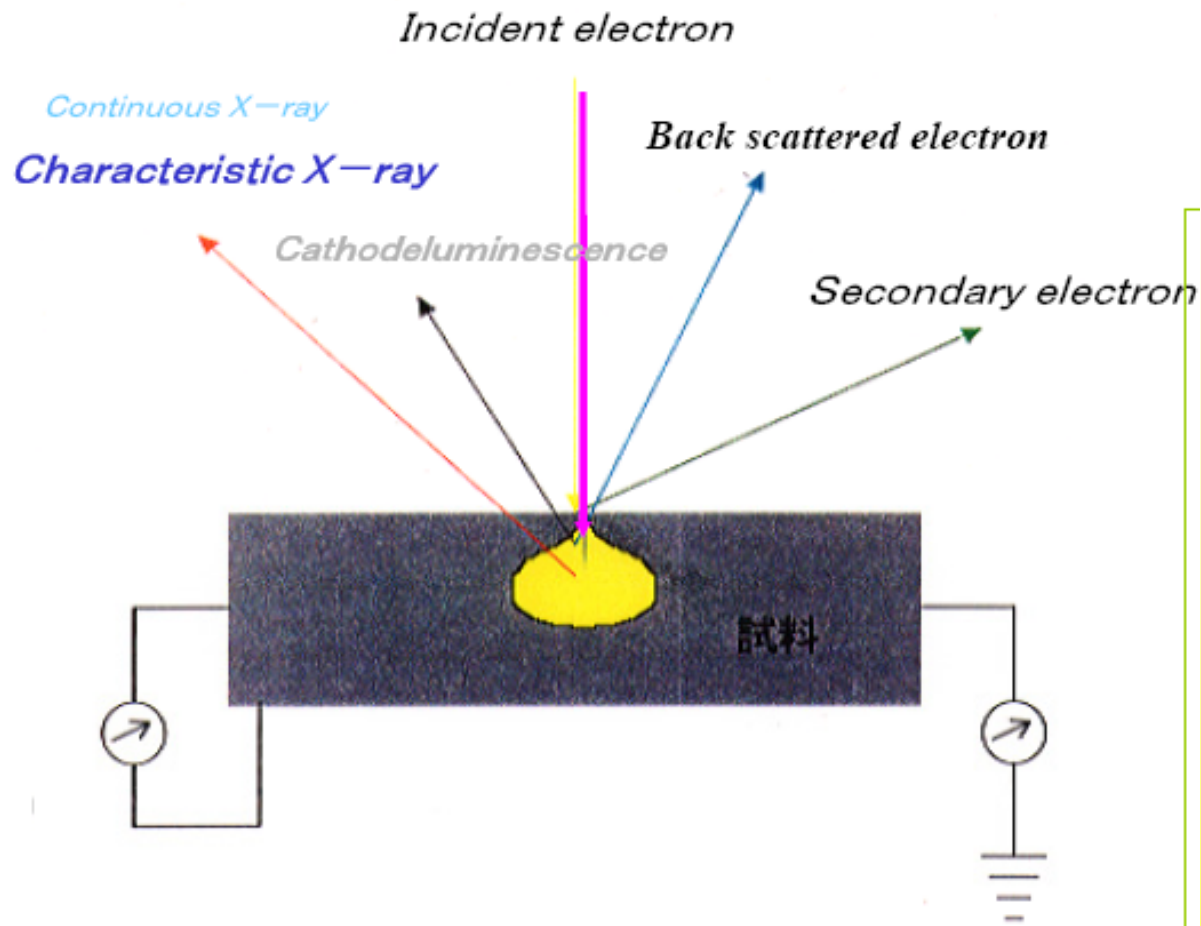
# Theory of Energy Dispersive Spectrometer

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## *Principle of EDX*

# Theory of Energy Dispersive Spectrometer

## Generation of X-ray



# Theory of Energy Dispersive Spectrometer

ELECTRON BEAM

Cathodoluminescence  
(Visible light)

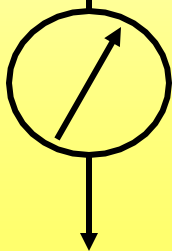
Characteristic  
X-rays

Secondary  
Electrons

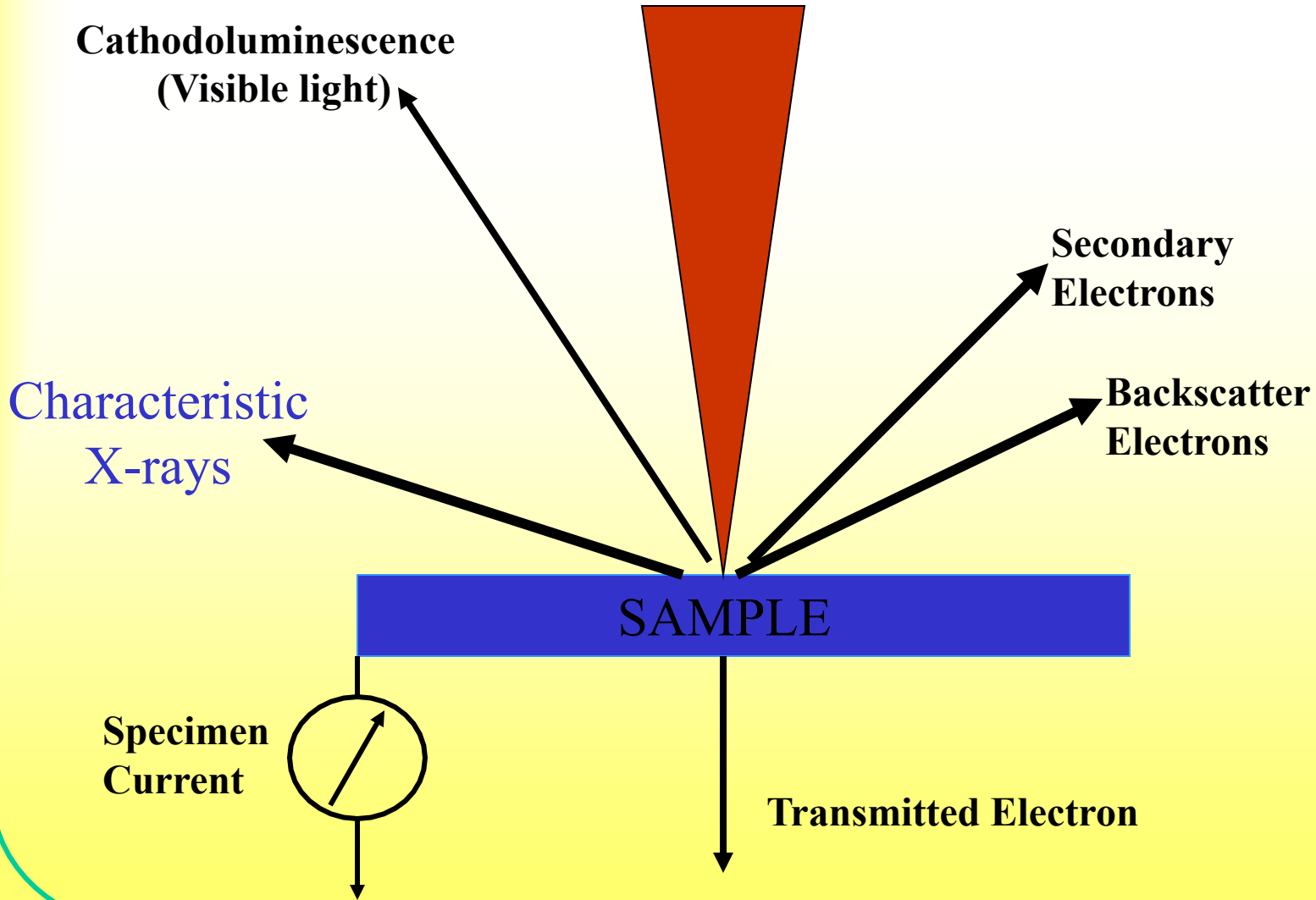
Backscatter  
Electrons

SAMPLE

Specimen  
Current



Transmitted Electron



# Theory of Energy Dispersive Spectrometer

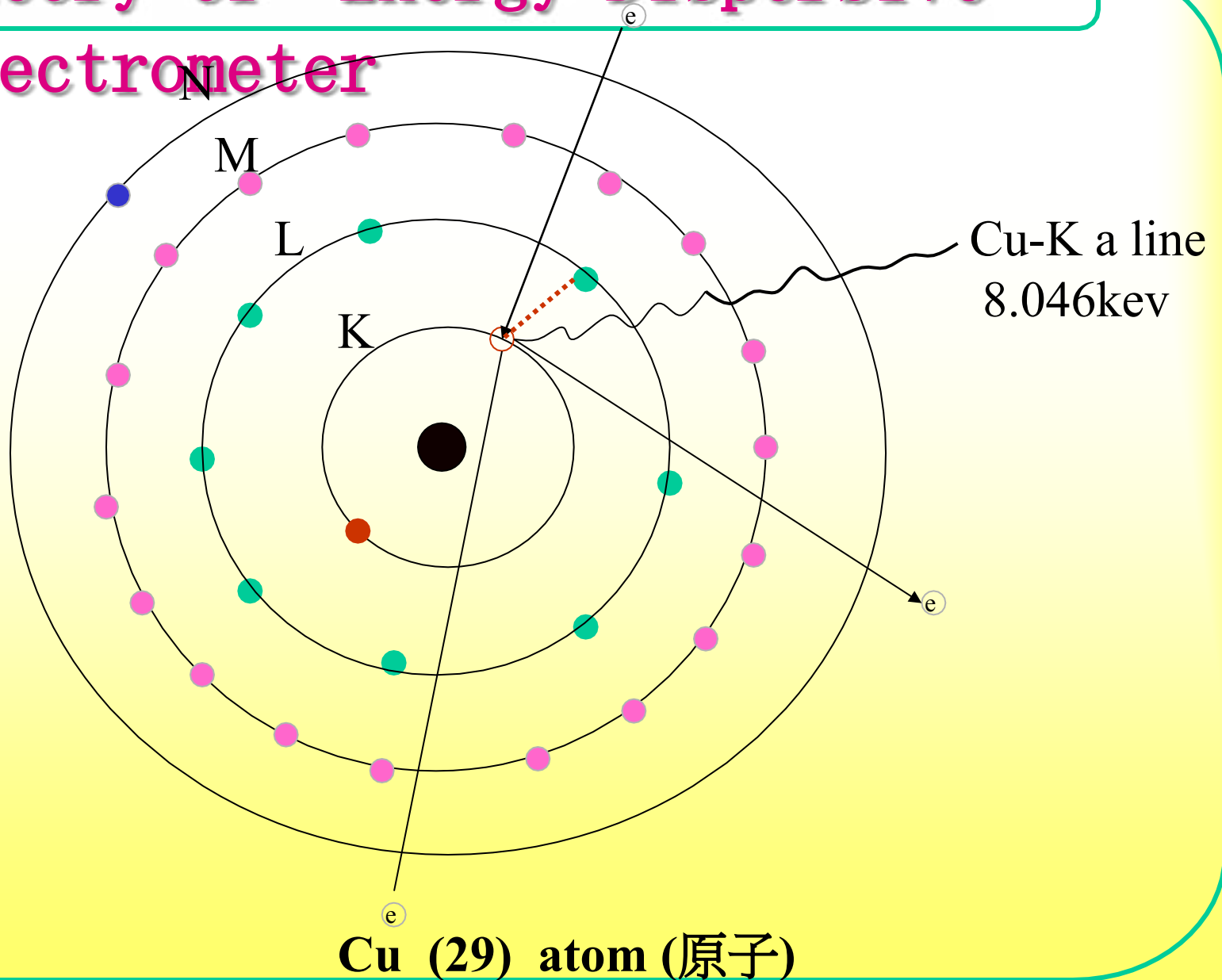
## ●特性X-光(Characteristic X-rays)

### 產生機構

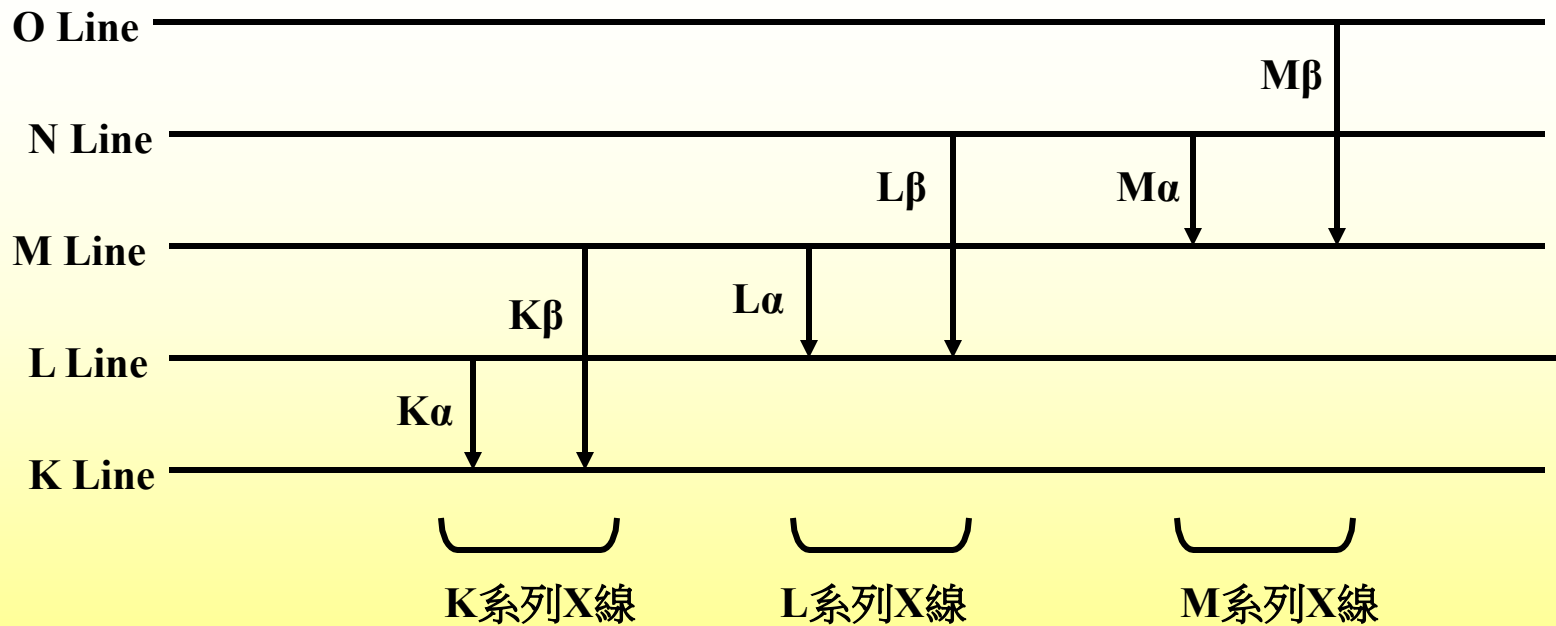
1. 電子或X-光激發原子內層電子
2. 外層電子填補空缺
3. 釋放出能量
4. 此能量激發出高階能階電子作為試片元素分析之依據



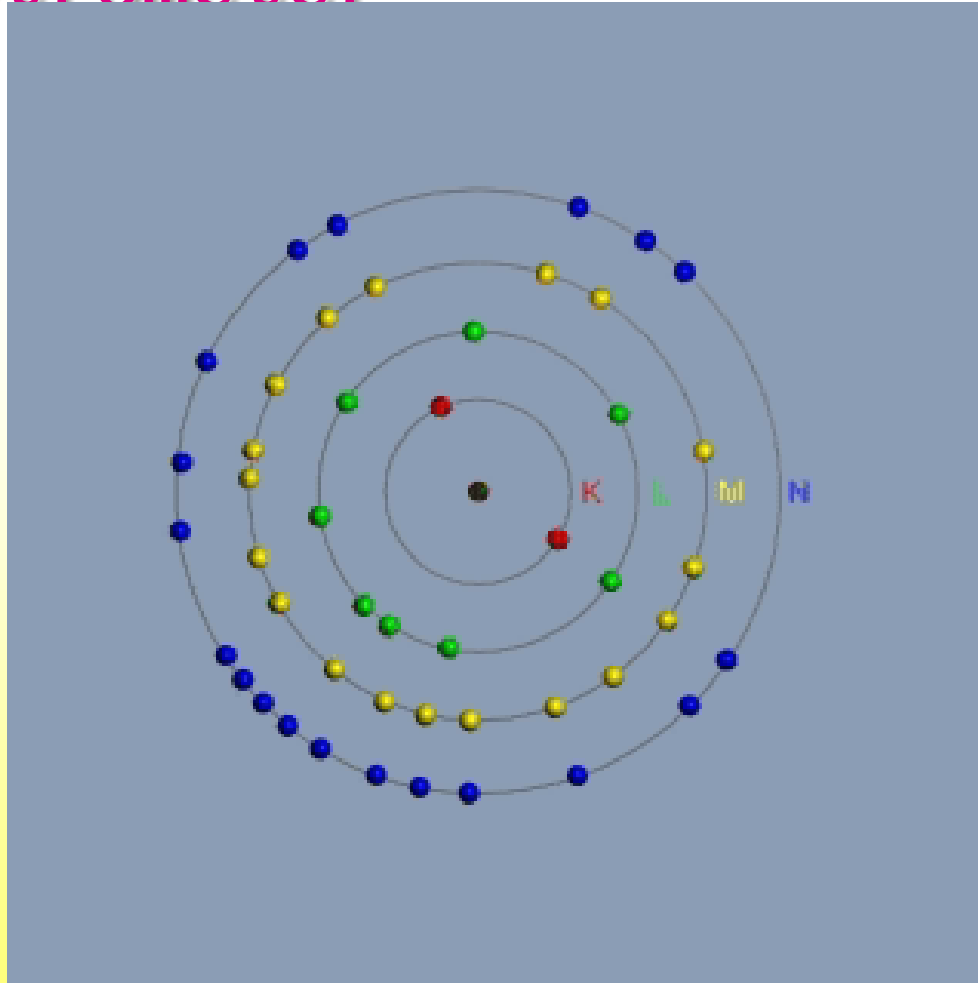
# Theory of Energy Dispersive Spectrometer



# Theory of Energy Dispersive Spectrometer



# Theory of Energy Dispersive Spectrometer



K line energy production

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